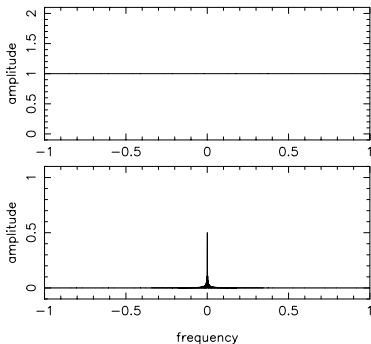
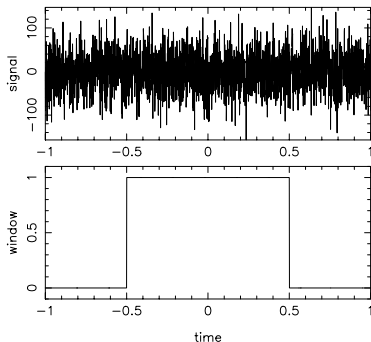


## Outline

- 1 Time Filtering
- 2 First-Order Transfer Function
- 3 Aliasing

## Finite Exposure and Time Resolution

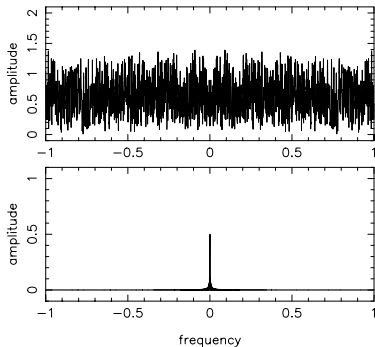
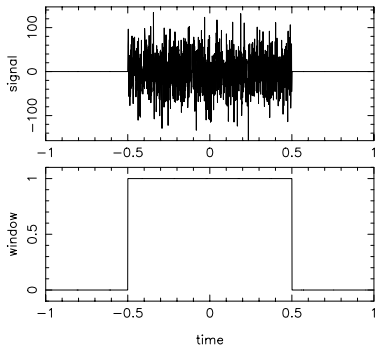
- measurement of stochastic process always takes place
  - over finite time period  $T$ , e.g. due to limited hours in one night
  - with time resolution  $\Delta T$ , e.g. due to finite exposure time
- sampling interval does not have to be the same as exposure time, e.g. CCD needs time to read out image
- *duty cycle* of measurement (typically expressed in %): ratio of exposure time to sampling interval
- in the following: assume 100% duty cycle



- limitation in measuring time  $T$  corresponds to *multiplication in time domain* of stochastic variable  $X(t)$  with window function  $\Pi(t/T)$

$$\begin{aligned}\Pi\left(\frac{t}{T}\right) &\equiv 1 && \text{for } |t| \leq \frac{1}{2}T \\ \Pi\left(\frac{t}{T}\right) &\equiv 0 && \text{for } |t| > \frac{1}{2}T\end{aligned}$$

## Limited Measuring Time (continued)

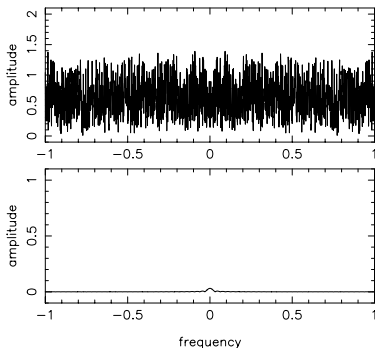
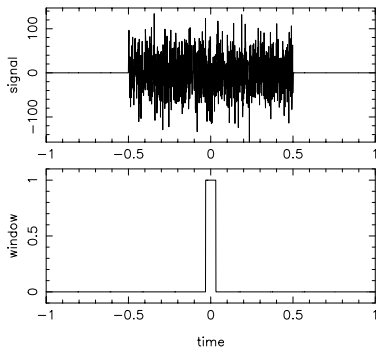


- new, time filtered, stochastic variable  $Y(t)$

$$Y(t) = \Pi\left(\frac{t}{T}\right) X(t)$$

- all measurements are limited in time

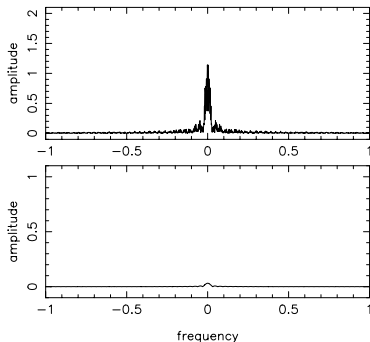
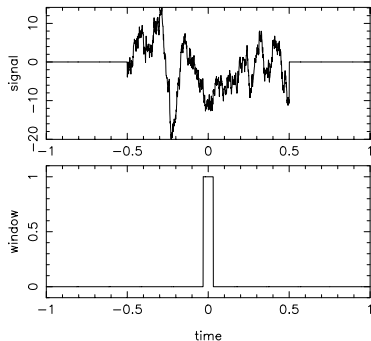
## Time Resolution



- measurement at time  $t$  with temporal resolution  $\Delta T$
- is integration of stochastic variable  $Y(t)$  between  $t - \Delta T/2$  and  $t + \Delta T/2$ , divided by  $\Delta T$  (running average)

$$Z(t) \equiv Y_{\Delta T}(t) = \frac{1}{\Delta T} \int_{t-\Delta T/2}^{t+\Delta T/2} Y(t') dt' = \frac{1}{\Delta T} \int_{-\infty}^{+\infty} \Pi\left(\frac{t-t'}{\Delta T}\right) Y(t') dt'$$

## Time Resolution (continued)

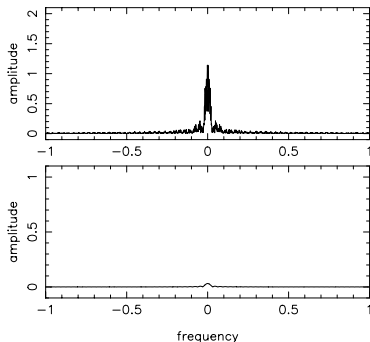
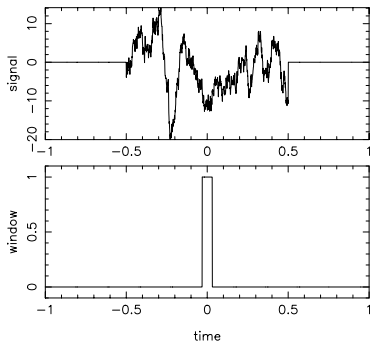


- express previous equation as convolution in time:

$$Z(t) \equiv Y_{\Delta T}(t) = \frac{1}{\Delta T} \int_{-\infty}^{+\infty} \Pi\left(\frac{t-t'}{\Delta T}\right) Y(t') dt'$$

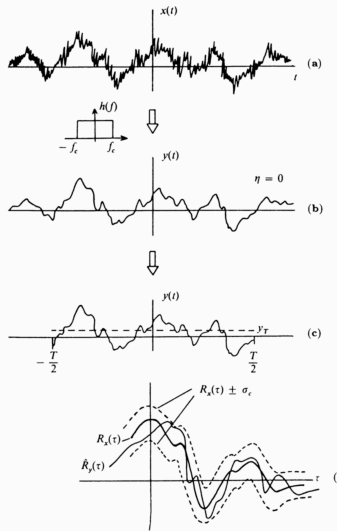
$$Z(t) = \frac{1}{\Delta T} \Pi\left(\frac{t}{\Delta T}\right) * Y(t) = \frac{1}{\Delta T} \Pi\left(\frac{t}{\Delta T}\right) * \Pi\left(\frac{t}{T}\right) X(t)$$

## Time Resolution (continued)



- low-frequency (or ‘low-pass’) filtering of stochastic variable  $Y(t)$
- limitation in time resolution always due to frequency-limited transmission characteristic of any physical measuring device
- $\mu_T$ ,  $R_T(\tau)$  for ergodic process obtained from finite measuring period  $T$  will slightly differ from true  $\mu$ ,  $R(\tau)$
- error introduced by measuring sample average  $\mu_T$  instead of  $\mu$

## Error Assessment in Sample Average $\mu_T$



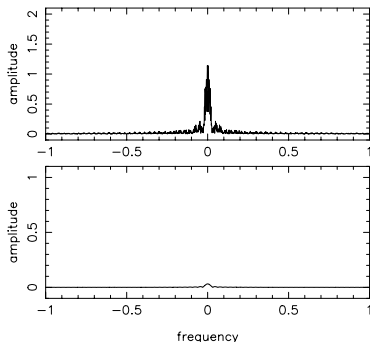
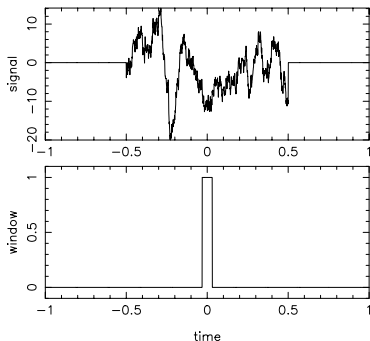
- accuracy with which approximate value  $\mu_T$  approaches real value  $\mu$
- determining average corresponds to convolution in time domain with block function

$$X(t) \rightarrow \boxed{\frac{1}{T} \Pi\left(\frac{t}{T}\right)} \rightarrow X_T$$

- in Fourier domain averaging corresponds to multiplication with sinc-function

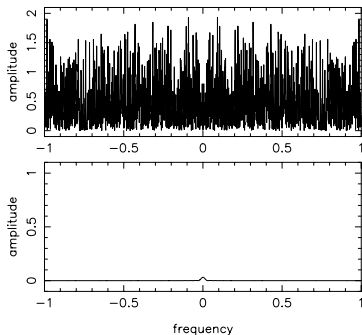
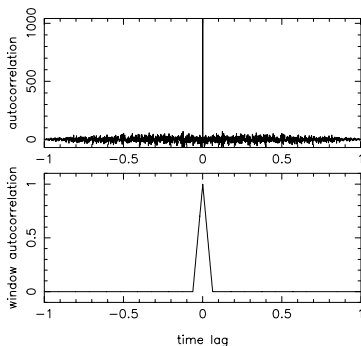


# Transfer Function



- influence of measuring device on signal described in Fourier domain:  $Y(f) = X(f)H(f)$ ,  $Y^*(f) = X^*(f)H^*(f)$
- $H(f)$  is *transfer function*
- therefore  $|Y(f)|^2 = |X(f)|^2 |H(f)|^2$
- *transfer function* used both for  $H(f)$  (signal transfer function) and  $|H(f)|^2$  (power transfer function)

## Autocorrelation in Fourier Domain



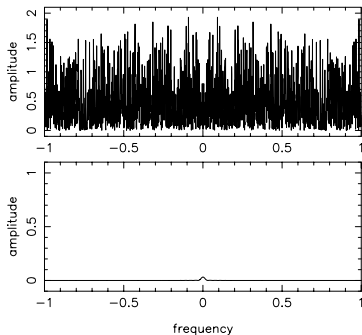
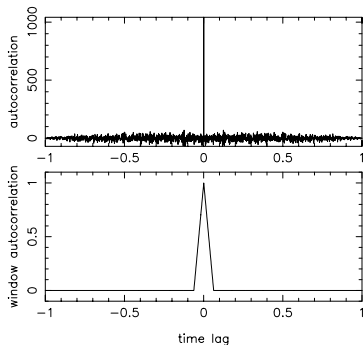
- Fourier transform of autocorrelation:

$$S_{X_T}(f) = |H(f)|^2 S_{X(t)}(f) = \text{sinc}^2(Tf) \cdot S_{X(t)}(f)$$

- transforming back to time domain

$$R_{X_T}(\tau) = h(\tau) * h(\tau) * R_{X(t)}$$

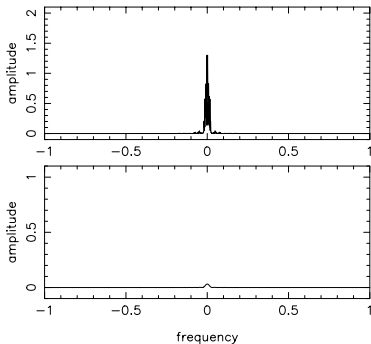
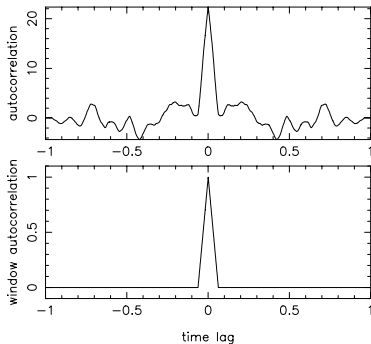
## Autocorrelation in Fourier Domain



- $h \equiv (1/T)\Pi(t/T)$  is real function
- convolution of block with itself is a triangle

$$h(\tau) * h(\tau) \equiv \rho(\tau) \equiv \frac{1}{T} \Lambda\left(\frac{\tau}{T}\right)$$

## Autocorrelation (continued)



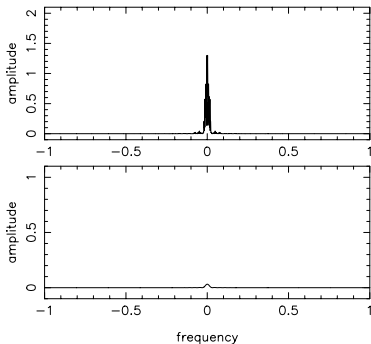
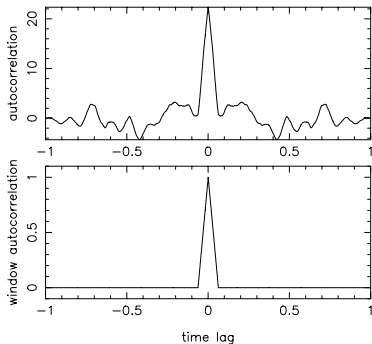
- from before

$$R_{X_T}(\tau) = h(\tau) * h(\tau) * R_{X(t)}$$

- rewrite as

$$R_{X_T}(\tau) = \frac{1}{T} \Lambda\left(\frac{\tau}{T}\right) * R_{X(t)} \equiv \frac{1}{T} \int_{-\infty}^{+\infty} \Lambda\left(\frac{\tau'}{T}\right) R_{X(t)}(\tau - \tau') d\tau'$$

## Autocorrelation (continued)



- consider  $\mu = 0$ , i.e.  $R = C$

$$C_{X_T}(\tau) = \frac{1}{T} \int_{-\infty}^{+\infty} \Lambda\left(\frac{\tau'}{T}\right) C_{X(t)}(\tau - \tau') d\tau'$$

- variance from time lag  $\tau = 0$  and  $C$  even

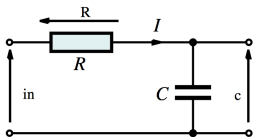
$$\begin{aligned}C_{X_T}(0) \equiv [\sigma_{X_T}]^2 &= \frac{1}{T} \int_{-\infty}^{+\infty} \Lambda\left(\frac{\tau'}{T}\right) C_{X(t)}(-\tau') d\tau' \\ &= \frac{1}{T} \int_{-\infty}^{+\infty} \Lambda\left(\frac{\tau'}{T}\right) C_{X(t)}(\tau') d\tau'\end{aligned}$$

- explicitly writing triangle function  $\Lambda$

$$[\sigma_{X_T}]^2 = \frac{1}{T} \int_{-T}^{+T} \left(1 - \frac{|\tau'|}{T}\right) C_{X(t)}(\tau') d\tau'$$

- integral over  $\pm T$ , normalization still  $1/T$
- autocovariance is *always* limited in frequency domain

## Example: First-Order Transfer Function



- *first-order system*: described by first-order differential equation

$$\tau_0 \frac{dY(t)}{dt} + Y(t) = X(t)$$

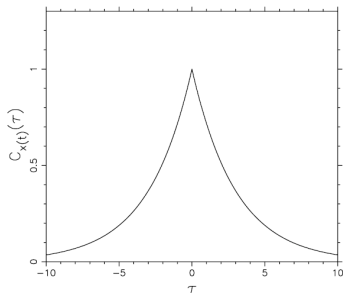
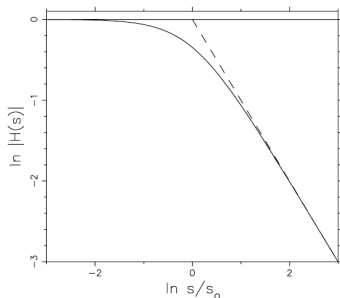
- RC circuit:  $\tau_0 = RC$
- Fourier transform differential equation

$$2\pi if\tau_0 Y(f) + Y(f) = X(f)$$

- first-order transfer function from  $Y(f) = H(f) * X(f)$ :

$$H(f) = \frac{1}{1 + 2\pi if\tau_0}$$

## Example: First-Order Transfer Function



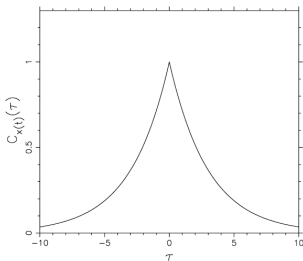
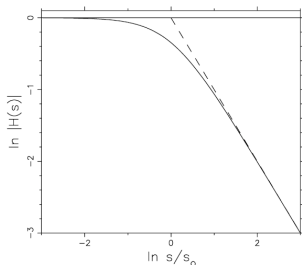
- first-order transfer function from before:

$$H(f) = \frac{1}{1 + 2\pi if\tau_0}$$

- $f \ll 1/(2\pi\tau_0) \equiv f_0$ , complete transfer,  $|H(f)| = 1$
- $f \gg f_0$ , transfer inversely proportional to  $f$ ,  $|H(f)| = f_0/f$
- cut-off frequency  $f_0$  of transfer function  $H(f)$



## Auto-Covariance of First-Order System



- without proof: autocovariance of first-order system drops exponentially with  $|\tau|$ :

$$C_{X(t)}(\tau) = C_{X(t)}(0)e^{-|\tau|/\tau_0} \quad \text{where} \quad \tau_0 \equiv \frac{1}{2\pi f_0}$$

- $\tau \gg \tau_0 \Rightarrow$  correlation virtually zero; integrate:

$$[\sigma_{X_T}]^2 = 2 [\sigma_{X(t)}]^2 \frac{\tau_0}{T} \left[ 1 - \frac{\tau_0}{T} \left( 1 - e^{-T/\tau_0} \right) \right]$$

## Auto-Covariance of First-Order System (continued)

- limiting case 1: duration of measurement much longer than correlation time,  $T \gg \tau_0$
- in general:

$$[\sigma_{X_T}]^2 = 2 [\sigma_{X(t)}]^2 \frac{\tau_0}{T} \left[ 1 - \frac{\tau_0}{T} \left( 1 - e^{-T/\tau_0} \right) \right]$$

- in limiting case 1

$$[\sigma_{X_T}]^2 = 2 [\sigma_{X(t)}]^2 \frac{\tau_0}{T} = \frac{[\sigma_{X(t)}]^2}{\pi f_0 T}$$

- variance proportional to variance of incoming signal
- variance approaches zero when duration of measurement goes to infinity
- variance approaches zero when measurement frequency goes to infinity

## Auto-Covariance of First-Order System (continued)

- from before

$$[\sigma_{X_T}]^2 = 2 [\sigma_{X(t)}]^2 \frac{\tau_o}{T} = \frac{[\sigma_{X(t)}]^2}{\pi f_o T}$$

- measured signal is *ergodic in the mean*
- limit can be understood by noting that  $f_o T$  is number of cycles during  $T$  with a frequency  $f_o$ , i.e. it gives number of measurements
- analogous to equation for variance of average  $\sigma_\mu^2 = \sigma^2/N$

## Auto-Covariance of First-Order System (continued)

- limiting case 2: duration of measurement equals correlation time,  $T = \tau_o$
- from before

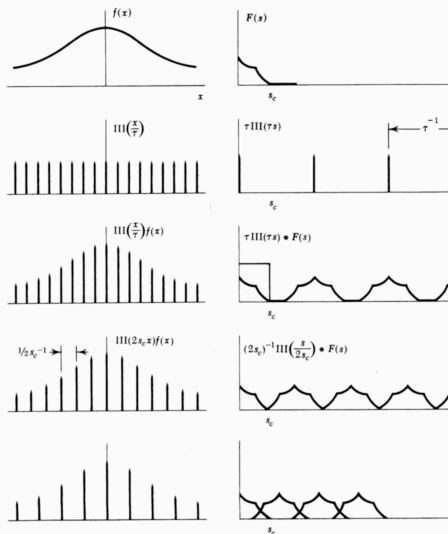
$$[\sigma_{X_T}]^2 = 2 [\sigma_{X(t)}]^2 \frac{\tau_o}{T} \left[ 1 - \frac{\tau_o}{T} \left( 1 - e^{-T/\tau_o} \right) \right]$$

- in this limiting case:

$$\sigma_{X_T}^2 = 2\sigma_{X(t)}^2 e^{-1} \simeq \sigma_{X(t)}^2$$

- understandable in terms of determining average in case of single measurement ( $N = 1$ )
- duration of measurement should be much longer than correlation time,  $T \gg \tau_o$ , to avoid *large* errors in estimates of average and variance
- must take into account errors in average and variance when looking for really *small* effects

# Nyquist Frequency

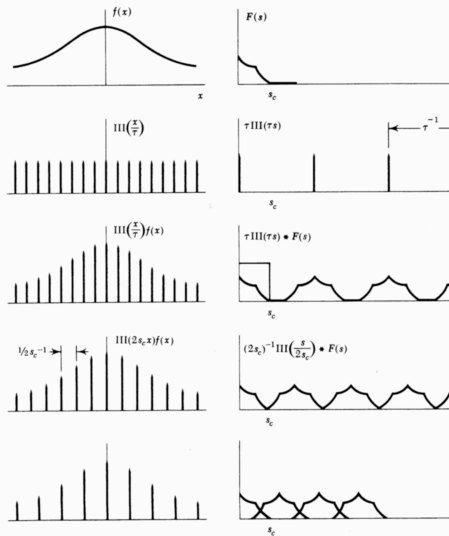


- signal  $S(x)$  subject to instrument response  $R(x)$
- resulting measurement

$$M(x) = S(x) * R(x)$$

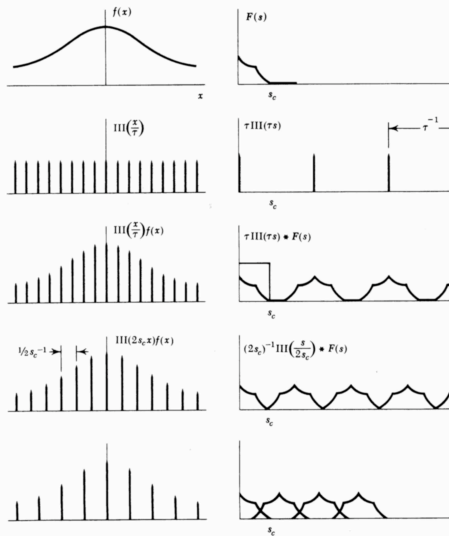
- finite frequency response of instrument  $\Rightarrow M(x)$  always bandwidth limited
- Fourier transform  $M(s) \Leftrightarrow M(x)$  is bandwidth-limited function
- characterized by cut-off frequency  $s_{max}$ , critical or Nyquist frequency ( $s_C$ )

## Nyquist Frequency (continued)



- gaussian response: impossible because no physical system transmits frequencies to  $\infty$
- Shannon and Nyquist established theorem for optimum sampling of band-limited observations
- theorem states that no information is lost if sampling occurs at intervals  $\tau = 1/(2s_c)$

## Regular Sampling

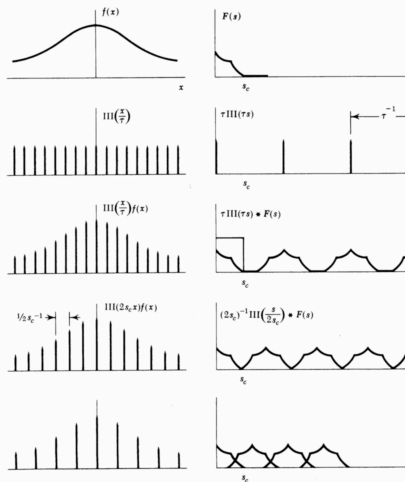


- $M(x)$  sampled at regular intervals,  $M(x) \rightarrow M(n\tau)$   
 $n$  integer  
 $\tau$  sampling interval
- describe sampling process quantitatively with Dirac comb (series of  $\delta$  functions at regular distances equal to 1):

$$\text{III}(x) \equiv \sum_{n=-\infty}^{\infty} \delta(x - n)$$

- extended comb to arbitrary distances:  
 $a \text{III}(ax) = \sum_n \delta(x - n/a)$

## Regular Sampling

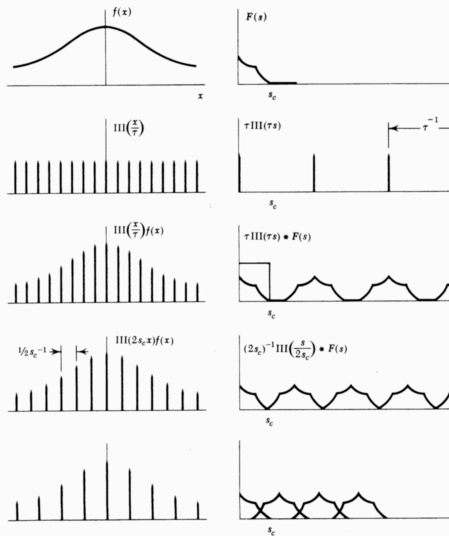


- write sampled signal  $M_S(x)$  as

$$\begin{aligned}
 M_S(x) &= \sum_n M(n\tau) \delta(x - n\tau) \\
 &= \frac{1}{\tau} \text{III}\left(\frac{x}{\tau}\right) M(x)
 \end{aligned}$$



## Regular Sampling (continued)

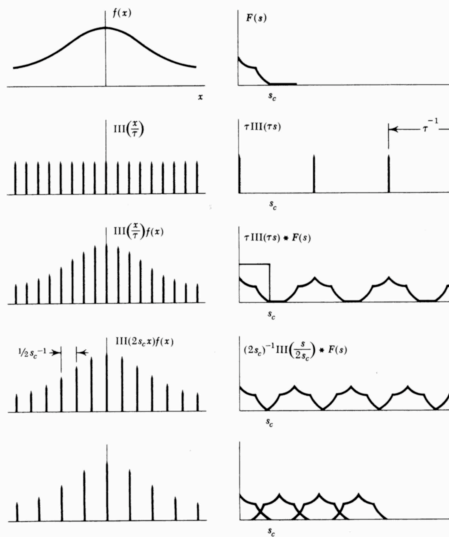


- Fourier transform pair  
 $M_S(s) \Leftrightarrow M_S(x)$

$$\begin{aligned}
 M_S(s) &= \text{III}(\tau s) * M(s) \\
 &= \frac{1}{\tau} \sum_n M\left(s - \frac{n}{\tau}\right)
 \end{aligned}$$

- except for factor  $1/\tau$ ,  $M_S(s)$  is series of replications of  $M(s)$  at intervals  $1/\tau$

## Regular Sampling (continued)



- $M(s)$  bandwidth-limited function with cut-off frequency  $s = s_c \Rightarrow$  fully recover single (i.e. not repeated) function  $M(s)$  from series by multiplication with  $\tau$  and by filtering with gate function  $\Pi(s/2s_c)$ :

$$\Pi\left(\frac{s}{2s_c}\right) \tau \text{III}(\tau s) * M(s) \Leftrightarrow 2s_c \text{sinc} 2s_c x * \text{III}\left(\frac{x}{\tau}\right) M(x)$$

## Regular Sampling (continued)

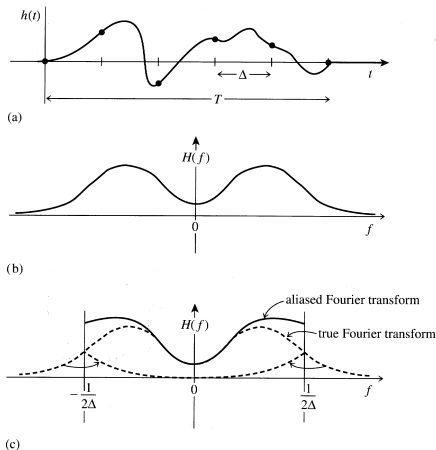
- reconstruct  $M(x)$  exactly if series of  $M(s)$  functions in frequency domain touch without overlap
- only possible by sampling at  $\tau = 1/(2s_c)$  (optimum sampling interval)
- convolution to fully reconstruct  $M(x)$ :

$$\begin{aligned}M(x) &= \int_{-\infty}^{+\infty} \text{sinc}\left(\frac{x-x'}{\tau}\right) \sum_n M(n\tau) \delta(x' - n\tau) dx' \\ &= \sum_n \text{sinc}\left(\frac{x-n\tau}{\tau}\right) M(n\tau)\end{aligned}$$

- check result for one sampling point  $x = j\tau$ , with  $\text{sinc}(j-n) = 1$  for  $j = n$  and  $= 0$  for  $j \neq n$ :

$$M(x) = M(j\tau)$$

# Aliasing



- function  $h(t)$  shown in top panel is undersampled
- sampling interval  $\Delta$  larger than  $\frac{1}{2f_{max}}$
- lower panel shows that power in frequencies above  $\frac{1}{2\Delta}$  is 'mirrored' with respect to this frequency
- produces aliased transform that deviates from true Fourier transform

Press et al. (1992)

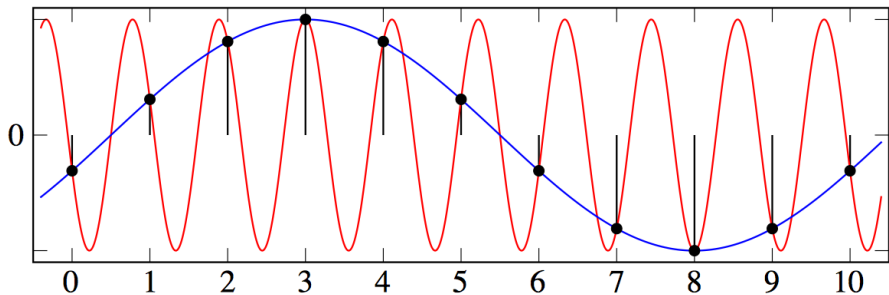
## Aliasing (continued)

- calculation of intermediate points from samples does not depend on calculating Fourier transforms
- equivalent operation in  $x$ -domain is direct convolution of  $2s_c \text{sinc} 2s_c x$  with  $\sum_{n=-\infty}^{\infty} \delta(x/n\tau) M(x)$
- omission of  $1/\tau$  factor ensures proper normalization in  $s$ -domain
- superposition of series of sinc-functions with weight factors  $M(n\tau)$ , i.e. the sample values, at intervals  $\tau$  exactly reconstruct the continuous function  $M(x)$
- sinc-functions provide proper interpolation between consecutive sample points
- sinc-function referred to as *interpolation function*

## Aliasing (continued)

- discrete Fourier transform causes no loss of information if sampling frequency  $\frac{1}{\tau}$  is twice the highest frequency in continuous input function
- maximum frequency  $s_{max}$  for given sampling interval is  $\frac{1}{2\tau}$
- input signal sampled too slowly (contains frequencies higher than  $\frac{1}{2\tau}$ )  $\Rightarrow$  source signal cannot be determined after sampling process
- loss of fine details
- must apply low-pass filter before sampling:
  - electronic low-pass filter for electrical signals
  - defocusing of telescope for imaging

## Aliasing in Fourier Domain



<http://en.wikipedia.org/wiki/File:AliasingSines.svg>

- unresolved, high frequencies beat with measured frequencies
- produce spurious components in frequency domain below Nyquist frequency
- may give rise to major problems and uncertainties in the determination of source function